

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14414-018001	Application No. 10/761,902
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))		Applicant Raluca Dinu et al.	
		Filing Date January 21, 2004	Group Art Unit 1653

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SA	AA	5,433,895	07/18/95	Jeng et al.			
	AB	5,631,735	05/20/97	Nagai et al.			
	AC	5,729,641	03/17/98	Chandonnet et al.			
	AD	6,525,867	02/25/03	Oakley et al.			
	AE	2002/0160282	10/31/02	Huang et al.			
SA	AF	2003/0085398	05/08/03	Koyama et al.			

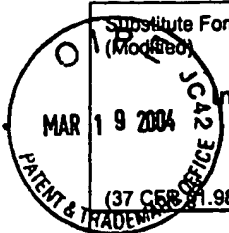
Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SA	AG	WO 01/40849	06/07/01	WIPO				
SA	AH	WO 04/55897	07/01/04	WIPO				
	AI							
	AJ							
	AK							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AL	
	AM	
	AN	
	AO	

Examiner Signature /Shamim Ahmed/ (09/27/2006)	Date Considered 09/27/2006
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SA	AA	5,120,339	06/09/92	Markovich et al.			
	AB	5,198,513	03/30/93	Clement et al.			
	AC	5,219,788	06/15/93	Abermathey et al.			
	AD	5,223,356	06/29/93	Kumar et al.			
	AE	5,370,969	12/06/94	Vidusek			
	AF	5,433,895	07/18/95	Jeng et al.			
	AG	5,480,687	01/02/96	Heming et al.			
	AH	5,497,445	03/05/96	Imoto			
	AI	5,635,576	06/03/97	Foll et al.			
	AJ	5,714,304	02/03/98	Gibbons et al.			
	AK	5,776,374	07/07/98	Newsham et al.			
	AL	5,783,319	07/21/98	Reisfeld et al.			
	AM	5,811,507	09/22/98	Chan et al.			
	AN	5,861,976	01/19/99	Hoekstra			
	AO	5,887,116	03/23/99	Grote			
	AP	6,002,828	12/14/99	Hult et al.			
	AQ	6,019,906	02/01/00	Jang et al.			
	AR	6,031,945	02/29/00	You et al.			
	AS	6,060,170	05/09/00	Burgoyne, Jr.			
	AT	6,117,967	09/12/00	Fuller, et al.			
	AU	6,126,867	10/03/00	Kanitz et al.			
	AV	6,229,949	05/08/01	Ido et al.			
	AW	6,294,573	09/25/01	Curtin et al.			
	AX	6,303,730	10/16/01	Fries et al.			
	AY	6,306,563	10/23/01	Xu et al.			
	AZ	6,323,361	11/27/01	Wu et al.			
↓	AAA	6,335,149	01/01/02	Xu et al.			
SA	ABB	6,419,989	07/16/02	Betz et al.			

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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SA	ACC	6,466,707	10/15/02	Dawes, et al.			
	ADD	6,473,551	10/29/02	Norwood, et al.			
	AEE	10/264,461	N/A	Dinu et al.			
SA	AFF	10/301,978	N/A	Huang et al.			

Foreign Patent Documents or Published Foreign Patent Applications

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							Yes	No
SA	AGG	961139	01/12/99	EP			X	
	AHH	10049443	02/20/98	JP			X	
	AII	2001255426	09/21/01	JP			X	
	AJJ	09258151	10/03/97	JP			X	
	AKK	10232323	09/02/98	JP			X	
SA	ALL	04238305	08/26/92	JP			X	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
SA	AMM	Bailey et al., "Step and flash imprint lithography: Template surface treatment and defect analysis," <i>J. Vac. Sci. Technol. B</i> , 2000, 18(6):3572-3577
SA	ANN	Chen et al., "Thermosetting Polyurethanes with Stable and Large Second-Order Optical Nonlinearity," <i>Macromolecules</i> , 1992, 25:4032-4035
SA	AOO	Grote et al., "Effect of conductivity and dielectric constant on the modulation voltage for optoelectronic devices based on nonlinear optical polymers," <i>Opt. Eng.</i> , 2001, 40(11):2464-2473
SA	APP	Ma et al., "A Novel Class of High-Performance Perfluorocyclobutane-Containing Polymers for Second-Order Nonlinear Optics," <i>Chem. Mater.</i> , 2000, 12:1187-1189
SA	AQQ	Ma et al., "Highly Efficient and Thermally Stable Nonlinear Optical Dendrimer for Electrooptics," <i>J. Am. Chem. Soc.</i> , 2001, 123:986-987
SA	ARR	Mao et al., "Progress toward Device-Quality Second-Order Nonlinear Optical Materials. 1. Influence of Composition and Processing Conditions on Nonlinearity, Temporal Stability, and Optical Loss," <i>Chem. Mater.</i> , 1998, 10:146-155
SA	ASS	Oh et al., "Electro-optic polymer modulators for 1.55 μm wavelength using phenyltetraene bridged chromophore in polycarbonate," <i>Appl. Phys. Lett.</i> , 2000, 76(24):3525-3527
SA	ATT	Resnick et al., "Release Layers for Contact and Imprint Lithography," <i>Semicon. Int.</i> , June 2002, online version, 7 pgs.

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